# Low Skew, 1-to-4, Differential-to-LVDS Fanout Buffer

**DATA SHEET** 

# **General Description**

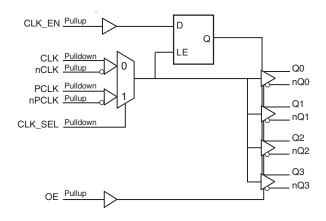
The ICS8543 is a low skew, high performance 1-to-4 Differential-to-LVDS Clock Fanout Buffer. Utilizing Low Voltage Differential Signaling (LVDS) the ICS8543 provides a low power, low noise, solution for distributing clock signals over controlled impedances of  $100\Omega.$  The ICS8543 has two selectable clock inputs. The CLK, nCLK pair can accept most standard differential input levels. The PCLK, nPCLK pair can accept LVPECL, CML, or SSTL input levels. The clock enable is internally synchronized to eliminate runt pulses on the outputs during asynchronous assertion/deassertion of the clock enable pin.

Guaranteed output and part-to-part skew characteristics make the ICS8543 ideal for those applications demanding well defined performance and repeatability.

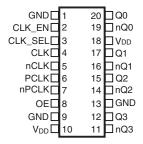
#### **Features**

- · Four differential LVDS output pairs
- Selectable differential CLK, nCLK or LVPECL clock inputs
- CLK, nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- PCLK, nPCLK pair can accept the following differential input levels: LVPECL, CML, SSTL
- Maximum output frequency: 800MHz
- Translates any single-ended input signals to LVDS levels with resistor bias on nCLK input
- Additive phase jitter, RMS: 0.164ps (typical)
- · Output skew: 40ps (maximum)
- Part-to-part skew: 500ps (maximum)
- Propagation delay: 2.6ns (maximum)
- Full 3.3V supply mode
- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

# **Block Diagram**



# **Pin Assignment**



ICS8543

20-Lead TSSOP 6.5mm x 4.4mm x 0.925mm package body G Package Top View



**Table 1. Pin Descriptions** 

Number	Name	Т	уре	Description
1, 9, 13	GND	Power		Power supply ground.
2	CLK_EN	Input	Pullup	Synchronizing clock enable. When HIGH, clock outputs follows clock input. When LOW, Qx outputs are forced low, nQx outputs are forced high. LVCMOS / LVTTL interface levels.
3	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects PCLK, nPCLK inputs. When LOW, selects CLK, nCLK inputs. LVCMOS / LVTTL interface levels.
4	CLK	Input	Pulldown	Non-inverting differential clock input.
5	nCLK	Input	Pullup	Inverting differential clock input.
6	PCLK	Input	Pulldown	Non-inverting differential LVPECL clock input.
7	nPCLK	Input	Pullup	Inverting differential LVPECL clock input.
8	OE	Input	Pullup	Output enable. Controls enabling and disabling of outputs Q[0:3], nQ[0:3]. LVCMOS/LVTTL interface levels.
10, 18	$V_{DD}$	Power		Positive supply pins.
11, 12	nQ3, Q3	Output		Differential output pair. LVDS interface levels.
14, 15	nQ2, Q2	Output		Differential output pair. LVDS interface levels.
16, 17	nQ1, Q1	Output		Differential output pair. LVDS interface levels.
19, 20	nQ0, Q0	Output		Differential output pair. LVDS interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

# **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ



#### **Function Tables**

**Table 3A. Control Input Function Table** 

	1	nputs		Out	puts
OE	CLK_EN	CLK_SEL	Selected Source	Q[0:3]	nQ[0:3]
0	X	X		Hi-Z	Hi-Z
1	0	0	CLK, nCLK	Disabled; Low	Disabled; High
1	0	1	PCLK, nPCLK	Disabled; Low	Disabled; High
1	1	0	CLK, nCLK	Enabled	Enabled
1	1	1	PCLK, nPCLK	Enabled	Enabled

After CLK\_EN switches, the clock outputs are disabled or enabled following a rising and falling input clock edge as shown in Figure 1. In the active mode, the state of the outputs are a function of the CLK/nCLK and PCLK/nPCLK inputs as described in Table 3B.

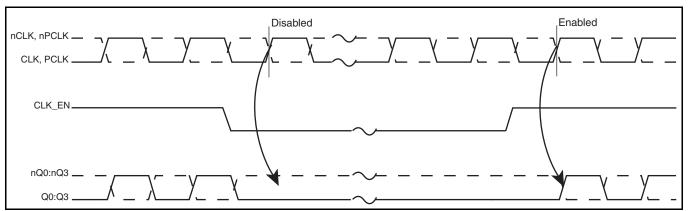


Figure 1. CLK\_EN Timing Diagram

**Table 3B. Clock Input Function Table** 

Inp	outs	Outputs			
CLK or PCLK	nCLK or nPCLK	Q[0:3]	nQ[0:3]	Input to Output Mode	Polarity
0	1	LOW	HIGH	Differential to Differential	Non-Inverting
1	0	HIGH	LOW	Differential to Differential	Non-Inverting
0	Biased; NOTE 1	LOW	HIGH	Single-Ended to Differential	Non-Inverting
1	Biased; NOTE 1	HIGH	LOW	Single-Ended to Differential	Non-Inverting
Biased; NOTE 1	0	HIGH	LOW	Single-Ended to Differential	Inverting
Biased; NOTE 1	1	LOW	HIGH	Single-Ended to Differential	Inverting

NOTE 1: Please refer to the Application Information section, Wiring the Differential Input to Accept Single-Ended Levels.



# **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>DD</sub>	4.6V
Inputs, V <sub>I</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, I <sub>O</sub> Continuos Current Surge Current	10mA 15mA
Package Thermal Impedance, $\theta_{JA}$	73.2°C/W (0 lfpm)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

# **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Positive Supply Voltage		3.135	3.3	3.465	V
I <sub>DD</sub>	Power Supply Current				50	mA

## Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = 3.3V \pm 5\%$ , $T_A = 0$ °C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V <sub>IH</sub>	Input High Voltage			2		3.765	V
V <sub>IL</sub>	Input Low Voltage					0.8	V
	Input High Current	OE, CLK_EN	$V_{DD} = V_{IN} = 3.465V$			5	μΑ
l IH	Input High Current	CLK_SEL	$V_{DD} = V_{IN} = 3.465V$			150	μΑ
	Input Low Current	OE, CLK_EN	$V_{DD} = 3.465V, V_{IN} = 0V$	-150			μΑ
¹  <u>L</u>	Input Low Current	CLK_SEL	$V_{DD} = 3.465V, V_{IN} = 0V$	-5			μΑ



Table 4C. Differential DC Characteristics,  $V_{DD}$  = 3.3V  $\pm$   $5\%,\,T_{A}$  =  $0^{\circ}C$  to  $70^{\circ}C$ 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	Input High Current	CLK	$V_{DD} = V_{IN} = 3.465V$			150	μΑ
Iн	Input High Current	nCLK	$V_{DD} = V_{IN} = 3.465V$			5	μΑ
	Input Low Current	CLK	$V_{DD} = 3.465V, V_{IN} = 0V$	-5			μA
I IIL	Input Low Current	nCLK	$V_{DD} = 3.465V, V_{IN} = 0V$	-150			μΑ
V <sub>PP</sub>	Peak-to-Peak Voltag	ge; NOTE 1		0.15		1.3	V
V <sub>CMR</sub>	Common Mode Inpu NOTE 1, 2	ıt Voltage;		0.5		V <sub>DD</sub> – 0.85	V

NOTE 1:  $V_{IL}$  should not be less than -0.3V. NOTE 2: Common mode input voltage is defined as  $V_{IH}$ .

Table 4D. LVPECL DC Characteristics,  $V_{DD} = 3.3 V \pm 5\%$ ,  $T_A = 0 ^{\circ} C$  to  $70 ^{\circ} C$ 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	Input High Current	PCLK	$V_{DD} = V_{IN} = 3.465V$			150	μΑ
Iн	input High Current	nPCLK	$V_{DD} = V_{IN} = 3.465V$			5	μΑ
	Input Low Current	PCLK	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-5			μΑ
IIL.	Input Low Current	nPCLK	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-150			μΑ
V <sub>PP</sub>	Peak-to-Peak Voltag	је		0.3		1.0	V
V <sub>CMR</sub>	Common Mode Inpu NOTE 1	it Voltage;		1.5		V <sub>DD</sub>	V

NOTE 1: Common mode input voltage is defined as  $\ensuremath{V_{IH}}.$ 

Table 4E. LVDS DC Characteristics,  $V_{DD}$  = 3.3V ± 5%,  $T_A$  = 0°C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OD</sub>	Differential Output Voltage		200	280	360	mV
$\Delta V_{OD}$	V <sub>OD</sub> Magnitude Change			0	40	mV
V <sub>OS</sub>	Offset Voltage		1.125	1.25	1.375	V
$\Delta V_{OS}$	V <sub>OS</sub> Magnitude Change			5	25	mV
l <sub>Oz</sub>	High Impedance Leakage		-10		+10	μΑ
I <sub>OFF</sub>	Power Off Leakage		-20	±1	+20	μΑ
I <sub>OSD</sub>	Differential Output Short Circuit Current			-3.5	-5	mA
Ios	Output Short Circuit Current			-3.5	-5	mA
V <sub>OH</sub>	Output Voltage High			1.34	1.6	V
V <sub>OL</sub>	Output Voltage Low		0.9	1.06		V



#### **AC Electrical Characteristics**

Table 5. AC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Maximum Output Fr	equency				800	MHz
t <sub>PD</sub>	Propagation Delay;	NOTE 1	<i>f</i> ≤ 800MHz	1.7		2.6	ns
<i>t</i> jit	Buffer Additive Phas refer to Additive Phas		153.6MHz, Integration Range: 12kHz – 20MHz		0.164		ps
tsk(o)	Output Skew; NOTE	2, 4				40	ps
tsk(pp)	Part-to-Part Skew; N	NOTE 3, 4				500	ps
$t_R / t_F$	Output Rise/Fall Tim	ne	20% to 80% @ 50MHz	150		350	ps
odc	Output Duty Cycle	odc		45	50	55	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: All parameters measured at 500MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at the differential output cross points.

NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltage, same frequency, same temperature and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

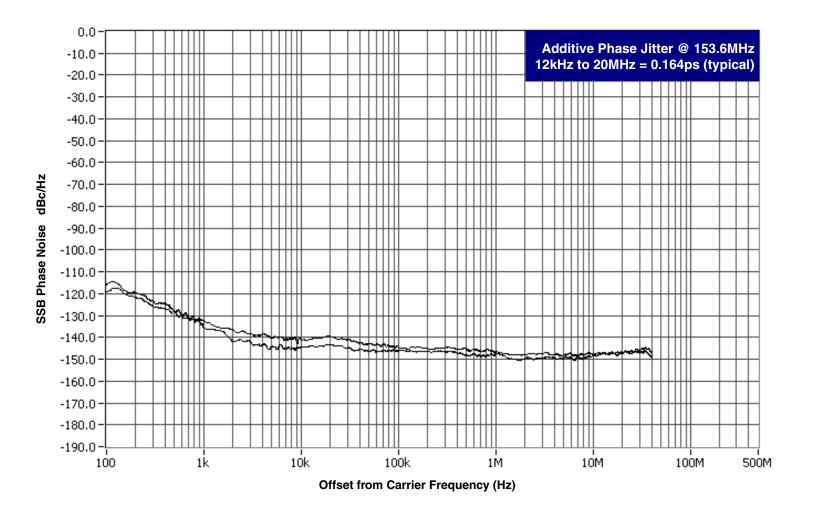
NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.



#### **Additive Phase Jitter**

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio

of the power in the 1Hz band to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

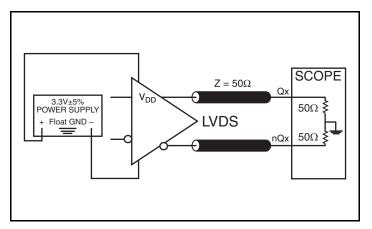


As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device. This

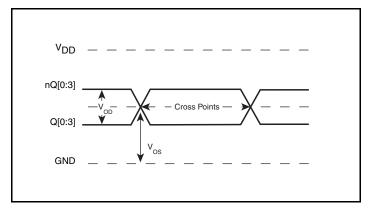
is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.



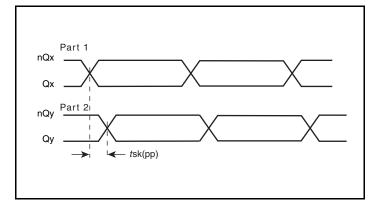
# **Parameter Measurement Information**



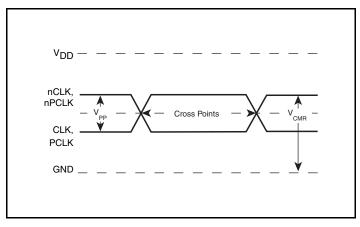
3.3V LVDS Output Load AC Test Circuit



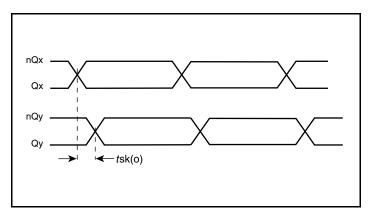
**Differential Output Level** 



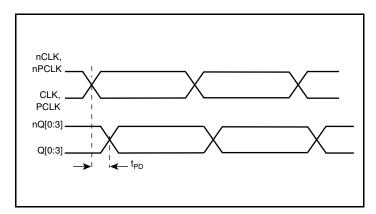
**Part-to-Part Skew** 



**Differential Input Level** 



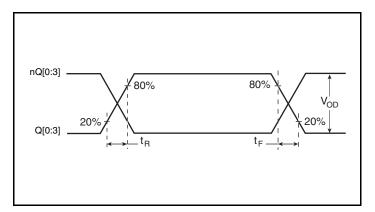
**Output Skew** 



**Propagation Delay** 



# **Parameter Measurement Information, continued**

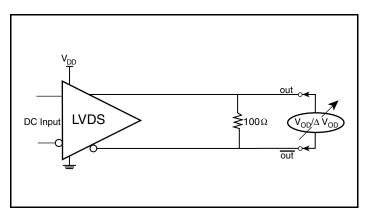


 $\begin{array}{c}
nQ[0:3] \\
Q[0:3] \\
\end{array}$   $odc = \frac{t_{PW}}{t_{PERIOD}} \times 100\%$ 

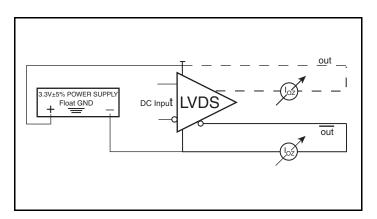
**Output Rise/Fall Time** 

DC Input LVDS  $\frac{50\Omega}{\text{out}} \stackrel{\text{out}}{\sim} \frac{50\Omega}{\text{vos}/\Delta \text{vos}}$ 

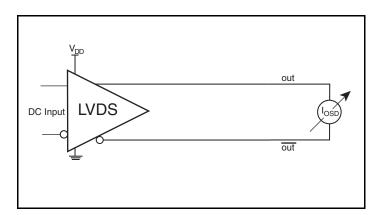
**Output Duty Cycle/Pulse Width/Period** 



**Offset Voltage Setup** 



**Differential Output Voltage Setup** 

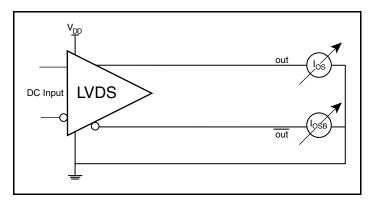


**High Impedance Leakage Current Setup** 

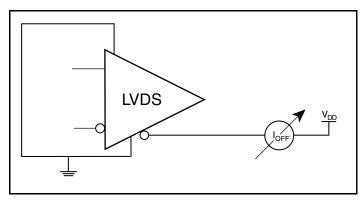
**Differential Output Short Circuit Setup** 



### **Parameter Measurement Information, continued**







Power Off Leakage Setup

# **Applications Information**

#### Wiring the Differential Input to Accept Single-Ended Levels

Figure 2 shows how a differential input can be wired to accept single ended levels. The reference voltage  $V_{REF} = V_{CC}/2$  is generated by the bias resistors R1 and R2. The bypass capacitor (C1) is used to help filter noise on the DC bias. This bias circuit should be located as close to the input pin as possible. The ratio of R1 and R2 might need to be adjusted to position the  $V_{REF}$  in the center of the input voltage swing. For example, if the input clock swing is 2.5V and  $V_{DD} = 3.3V$ , R1 and R2 value should be adjusted to set  $V_{REF}$  at 1.25V. The values below are for when both the single ended swing and  $V_{DD}$  are at the same voltage. This configuration requires that the sum of the output impedance of the driver (Ro) and the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the input will attenuate the signal in half. This can be done in one of two ways. First, R3 and R4 in parallel should equal the transmission

line impedance. For most  $50\Omega$  applications, R3 and R4 can be  $100\Omega$ . The values of the resistors can be increased to reduce the loading for slower and weaker LVCMOS driver. When using single-ended signaling, the noise rejection benefits of differential signaling are reduced. Even though the differential input can handle full rail LVCMOS signaling, it is recommended that the amplitude be reduced. The datasheet specifies a lower differential amplitude, however this only applies to differential signals. For single-ended applications, the swing can be larger, however  $V_{\rm IL}$  cannot be less than -0.3V and  $V_{\rm IH}$  cannot be more than  $V_{\rm DD}$  + 0.3V. Though some of the recommended components might not be used, the pads should be placed in the layout. They can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a differential signal.

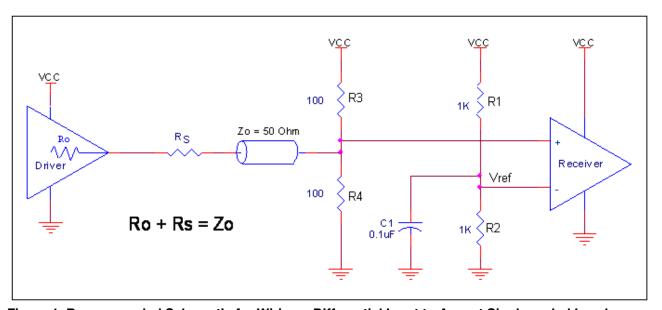


Figure 1. Recommended Schematic for Wiring a Differential Input to Accept Single-ended Levels



#### 3.3V Differential Clock Input Interface

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both  $V_{SWING}$  and  $V_{OH}$  must meet the  $V_{PP}$  and  $V_{CMR}$  input requirements. *Figures 3A to 3F* show interface examples for the CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples only.

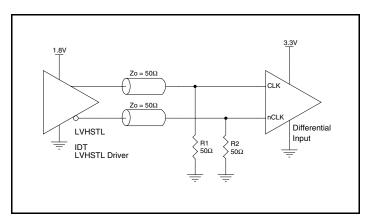


Figure 3A. CLK/nCLK Input Driven by an IDT Open Emitter LVHSTL Driver

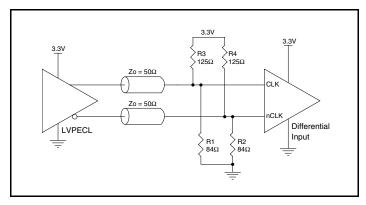


Figure 3C. CLK/nCLK Input Driven by a 3.3V LVPECL Driver

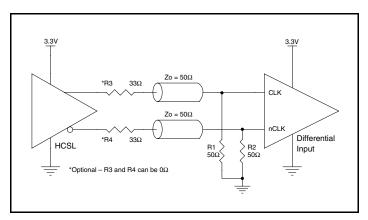


Figure 3E. CLK/nCLK Input Driven by a 3.3V HCSL Driver

Please consult with the vendor of the driver component to confirm the driver termination requirements. For example, in Figure 3A, the input termination applies for IDT open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

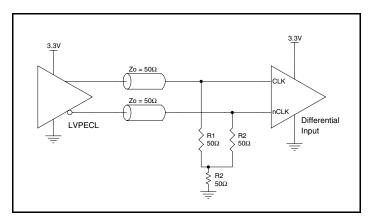


Figure 3B. CLK/nCLK Input Driven by a 3.3V LVPECL Driver

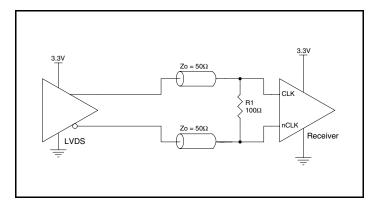


Figure 3D. CLK/nCLK Input Driven by a 3.3V LVDS Driver

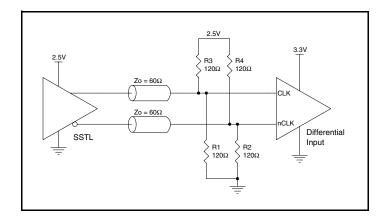


Figure 3F. CLK/nCLK Input Driven by a 2.5V SSTL Driver



## 3.3V LVPECL Clock Input Interface

The PCLK/nPCLK accepts LVPECL, CML, SSTL and other differential signals. Both  $V_{SWING}$  and  $V_{OH}$  must meet the  $V_{PP}$  and  $V_{CMR}$  input requirements. Figures 4A to 4E show interface examples for the PCLK/nPCLK input driven by the most common driver types.

 $\begin{array}{c|c}
3.3V & 3.3V \\
\hline
Zo = 50\Omega & 50\Omega
\end{array}$   $\begin{array}{c|c}
R_1 & R_2 \\
\hline
SO\Omega & 50\Omega
\end{array}$ 

Figure 4A. PCLK/nPCLK Input Driven by a CML Driver

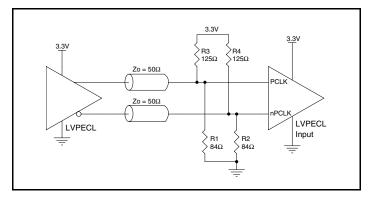


Figure 4C. PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver

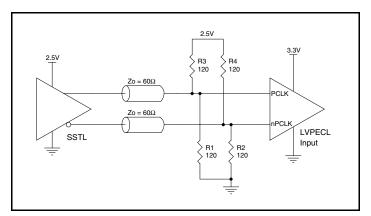


Figure 4E. PCLK/nPCLK Input Driven by a 2.5V SSTL Driver

The input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

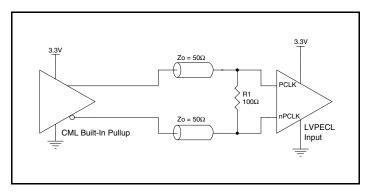


Figure 4B. PCLK/nPCLK Input Driven by a Built-In Pullup CML Driver

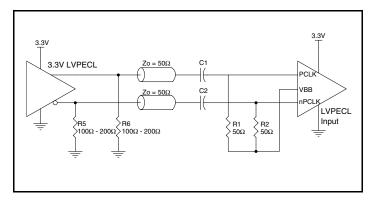


Figure 4D. PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver with AC Couple



#### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **CLK/nCLK INPUTS**

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a  $1k\Omega$  resistor can be tied from CLK to ground.

#### **PCLK/nPCLK INPUTS**

For applications not requiring the use of the differential input, both PCLK and nPCLK can be left floating. Though not required, but for additional protection, a  $1 k\Omega$  resistor can be tied from PCLK to ground.

#### **LVCMOS Control Pins**

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1 \mathrm{k}\Omega$  resistor can be used.

#### **Outputs:**

#### **LVDS Outputs**

All unused LVDS outputs should be terminated with 100 $\Omega$  resistor between the differential pair.

#### **LVDS Driver Termination**

A general LVDS interface is shown in Figure 5. Standard termination for LVDS type output structure requires both a  $100\Omega$  parallel resistor at the receiver and a  $100\Omega$  differential transmission line environment. In order to avoid any transmission line reflection issues, the  $100\Omega$  resistor must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The standard

termination schematic as shown in Figure 5 can be used with either type of output structure. If using a non-standard termination, it is recommended to contact IDT and confirm if the output is a current source or a voltage source type structure. In addition, since these outputs are LVDS compatible, the amplitude and common mode input range of the input receivers should be verified for compatibility with the output.

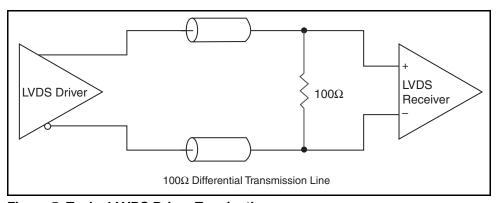


Figure 5. Typical LVDS Driver Termination



#### **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS8543. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS8543 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

Power (core)<sub>MAX</sub> = V<sub>DD MAX</sub> \* I<sub>DD MAX</sub> = 3.465V \* 50mA = 173.25mW

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature, Tj, to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 73.2°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}\text{C} + 0.173\text{W} * 73.2^{\circ}\text{C/W} = 82.7^{\circ}\text{C}$ . This is below the limit of  $125^{\circ}\text{C}$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 6. Thermal Resitance  $\theta_{JA}$  for 20 Lead TSSOP, Forced Convection

$\theta_{JA}$ by Velocity					
Linear Feet per Minute	0	200	500		
Single-Layer PCB, JEDEC Standard Test Boards	114.5°C/W	98.0°C/W	88.0°C/W		
Multi-Layer PCB, JEDEC Standard Test Boards	73.2°C/W	66.6°C/W	63.5°C/W		



# **Reliability Information**

Table 7.  $\theta_{\text{JA}}$  vs. Air Flow Table for a 20 Lead TSSOP

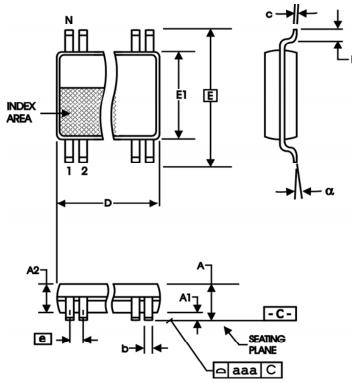
$\theta_{\sf JA}$ by Velocity					
Linear Feet per Minute	0	200	500		
Single-Layer PCB, JEDEC Standard Test Boards	114.5°C/W	98.0°C/W	88.0°C/W		
Multi-Layer PCB, JEDEC Standard Test Boards	73.2°C/W	66.6°C/W	63.5°C/W		

#### **Transistor Count**

The transistor count for ICS8543 is: 636

# **Package Outline and Package Dimensions**

Package Outline - G Suffix for 20 Lead TSSOP



**Table 8. Package Dimensions** 

All Dimensions in Millimeters				
Symbol	Minimum Maximum			
N	20			
Α		1.20		
A1	0.05	0.15		
A2	0.80	1.05		
b	0.19	0.30		
С	0.09	0.20		
D	6.40	6.60		
E	6.40 Basic			
E1	4.30	4.50		
е	0.65 Basic			
L	0.45	0.75		
α	0°	8°		
aaa		0.10		

Reference Document: JEDEC Publication 95, MO-153



# **Ordering Information**

# **Table 9. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8543BG	ICS8543BG	20 Lead TSSOP	Tube	0°C to 70°C
8543BGT	ICS8543BG	20 Lead TSSOP	2500 Tape & Reel	0°C to 70°C
8543BGLF	ICS8543BGLF	"Lead-Free" 20 Lead TSSOP	Tube	0°C to 70°C
8543BGLFT	ICS8543BGLF	"Lead-Free" 20 Lead TSSOP	2500 Tape & Reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.



# **Revision History Sheet**

Rev	Table	Page	Description of Change	Date
Α	T4E	5	In the V <sub>OL</sub> row, 1.06 has been moved to the Typical column from the maximum column.	9/18/01
Α		3	Updated Figure 1, CLK_EN Timing Diagram.	10/17/01
Α		3	Updated Figure 1, CLK_EN Timing Diagram.	11/2/01
Α		1 6 - 10	Features section, Bullet 6 to read 3.3V LVDS levels instead of LVPECL.  Updated Parameter Measurement Information figures.	5/6/02
В	T5	5	AC Characteristics table - revised Output Frequency from 650MHz to 800MHz.	6/5/02
С	4E	1 5	Features - deleted bullet "Designed to meet or exceed the requirements of ANSI TIA/EIA-644".  LVDS Table - changed V <sub>OD</sub> typical value from 350mV to 280mV.	9/19/02
D	T2	2 4 9 10 11	Pin Characteristics - changed C <sub>IN</sub> 4pF max. to 4pF typical.  Absolute Maximum Ratings - changed Output rating.  Added Differential Clock Input Interface section.  Added LVPECL Clock Input Interface section.  Added LVDS Driver Termination section.  Updated format throughout data sheet.	12/31/03
D	T1	2	Pin Description table - added function description to the OE pin.	4/7/04
D	Т8	10 13	Updated LVPECL Clock Input Interface section.  Added Lead Free part number to Ordering Information table.	6/16/04
D		3 10 11 12 13	Updated Figure 1, CLK_EN Timing Diagram. Updated Differential Clock Input Interface section. Updated LVPECL Clock Input Interface section. Added Recommendation for Unused Input and Output Pins section. Added Power Considerations section. Updated format throughout the datasheet.	2/27/08
Е	T5	1 6 7 10 11 12 13 16	Features section - added Additive Phase Jitter bullet.  AC Characteristics Table - added Added Phase Jitter spec and thermal note.  Added Additive Phase Jitter plot.  Updated Wiring the Differential Input to Accept Single-ended Levels section.  Updated 3.3V Differential Clock Input Interface section.  Updated 3.3V LVPECL Clock Input Interface section.  Updated LVDS Driver Termination section.  Ordering Information Table - deleted "ICS" prefix from Part/Order Number column.  Updated datasheet header/footer style.	11/12/10
E		1 14	Page 1, corrected Header Title.  Power Considerations - corrected typo for junction temperature from 827.7°C to 82.7°C.	12/17/10



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